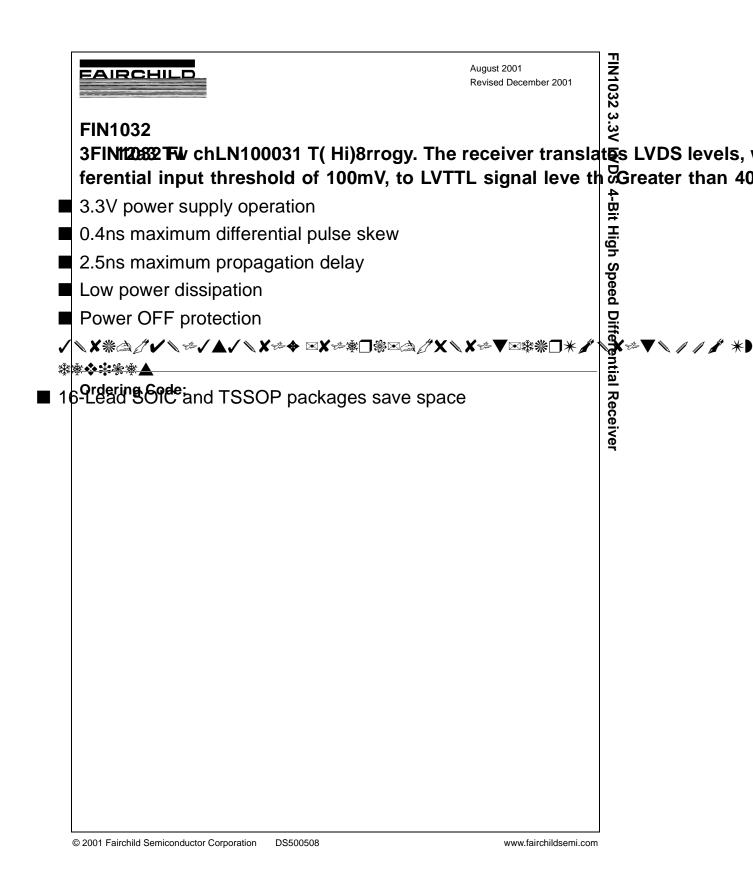
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Please note: As part of the Fairchild Semiconductor integration, some of the Fairchild orderable part numbers will need to change in order to meet ON Semiconductor's system requirements. Since the ON Semiconductor product management systems do not have the ability to manage part nomenclature that utilizes an underscore (_), the underscore (_) in the Fairchild part numbers will be changed to a dash (-). This document may contain device numbers with an underscore (_). Please check the ON Semiconductor website to verify the updated device numbers. The most current and up-to-date ordering information can be found at www.onsemi.com. Please email any questions regarding the system integration to Fairchild questions@onsemi.com.

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Absolute Maximum Ratings(Note 1)

Supply Voltage (V _{CC})	-0.5V to +4.6 V
Supply voltage (v _{CC})	-0.3 10 +4.0 1
DC Input Voltage (V _{IN})	-0.5V to +4.6 V
DC Input Voltage (V _{OUT})	-0.5V to 6 V
DC Output Current (I _O)	16 mA
Storage Temperature Range (T _{STG})	$-65^{\circ}C$ to $+150^{\circ}C$
Max Junction Temperature (T _J)	150°C
Lead Temperature (T _L)	
(Soldering, 10 seconds)	260°C
ESD (Human Body Model)	≥ 10,000 V
ESD (Machine Model)	≥ 500 V

Recommended Operating Conditions

Supply Voltage (V _{CC})	3.0 V to 3.6 V
Magnitude of Differential Voltage	
(V _{ID})	100 mV to $V_{\mbox{\scriptsize CC}}$
Common-Mode Input Voltage (VIC)	0.05 V to 2.35V
Input Voltage (V _{IN})	0 to V _{CC}
Operating Temperature (T _A)	$-40^{\circ}C$ to $+85^{\circ}C$
Note 1: The "Absolute Maximum Patings": are tho	se values beyond which

Note 1: The "Absolute Maximum Ratings": are those values beyond which damage to the device may occur. The databook specifications should be met, without exception, to ensure that the system design is reliable over its power supply, temperature and output/nput loading variables. Fairchild does not recommend operation of circuits outside databook specification.

DC Electrical Characteristics

Over supply voltage and operating temperature ranges, unless otherwise specified

Symbol	Parameter	Test Conditions	Min	Typ (Note 2)	Max	Units
V _{TH}	Differential Input Threshold HIGH	See Figure 1 and Table 1			100	mV
V _{TL}	Differential Input Threshold LOW	See Figure 1 and Table 1	-100			mV
I _{IN}	Input Current	$V_{IN} = 0V \text{ or } V_{CC}$			±20	μΑ
I _{I(OFF)}	Power-OFF Input Current	$V_{CC} = 0V$, $V_{IN} = 0V$ or 3.6V			±20	μΑ
V _{IH}	Input High Voltage (EN or EN)		2.0		V _{CC}	V
VIL	Input Low Voltage (EN or EN)		GND		0.8	V
V _{OH}	Output HIGH Voltage	$I_{OH} = -100 \ \mu A$	V _{CC} -0.2			v
		$I_{OH} = -8 \text{ mA}$	2.4			v
V _{OL}	Output LOW Voltage	I _{OH} = 100 μA			0.2	v
		I _{OL} = 8 mA			0.5	v
VIK	Input Clamp Voltage	$I_{IK} = -18 \text{ mA}$	-1.5			V
I _{OZ}	Disabled Output Leakage Current	EN = 0.8 and \overline{EN} = 2V, V_{OUT} = 3.6V or 0V			±20	μA
I _{OS}	Output Short Circuit Test	Receiver Enabled, $V_{OUT} = 0V$	-15		-100	mA
		(one output shorted at a time)	-15		-100	ША
I _{CCZ}	Disabled Power Supply Current	Receiver Disabled			5	mA
I _{CC}	Power Supply Current	Receiver Enabled, ($R_{IN+}{=}1V$ and $R_{IN-}{=}1.4V)$			15	mA
		or (R _{IN+} = 1.4V and R _{IN-} = 1V)			.0	
I _{PU/PD}	Output Power Up/Power Down	$V_{CC} = 0V$ to 1.5V			±20	μΑ

Note 2: All typical values are at $T_A=25^\circ C$ and with $V_{CC}=3.3 V.$

Over supply voltage and operating temperature ranges, unless otherwise specified

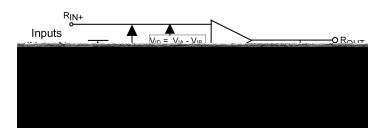
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Symbol	Parameter	Test Conditions	Min	Typ (Note 3)	Max	Units
t _{PLH}	Propagation Delay LOW-to-HIGH		1.0		2.5	ns
t _{PHL}	Propagation Delay HIGH-to-LOW		1.0		2.5	ns
t _{TLH}	Output Rise Time (20% to 80%)	V _{ID} = 400 mV, C _L = 10 pF,		0.7	1.2	ns
t _{THL}	Output Fall Time (80% to 20%)	$R_L = 1k\Omega$		0.7	1.2	ns
t _{SK(P)}	Pulse Skew t _{PLH} - t _{PHL}	See Figure 1 and Figure 2			0.4	ns
t _{SK(LH)}	Channel-to-Channel Skew				0.3	ns
t _{SK(HL)}	(Note 4)				0.5	115
t _{SK(PP)}	Part-to-Part Skew (Note 5)				1.0	ns
f _{MAX}	Maximum Operating Frequency (Note 6)	$R_L = 1k\Omega$, $C_L = 10 \text{ pF}$, see Figure 1 and Figure 2	200	325		MHz
t _{ZH}	LVTTL Output Enable Time from Z to HIGH				5.0	ns
t _{ZL}	LVTTL Output Enable Time from Z to LOW	$R_L = 1k\Omega$, $C_L = 10 \text{ pF}$,			5.0	ns
t _{HZ}	LVTTL Output Disable Time from HIGH to Z	See Figure 3 and Figure 4			5.0	ns
t _{LZ}	LVTTL Output Disable Time from LOW to Z	7			5.0	ns

Note 3: All typical values are at $T_A = 25^{\circ}C$ and with $V_{CC} = 3.3V$.

Note 4: $t_{SK(LH)}$, $t_{SK(HL)}$ is the skew between specified outputs of a single device when the outputs have identical loads and are switching in the same direction.

Note 5: $t_{SK(PP)}$ is the magnitude of the difference in propagation delay times between any specified terminals of two devices switching in the same direction (either LOW-to-HIGH or HIGH-to-LOW) when both devices operate with the same supply voltage, same temperature, and have identical test circuits. Note 6: f_{MAX} Criteria: Input $t_R = t_F < 1$ ns, $V_{ID} = 300$ mV, (1.05V to 1.35V pp), 50% duty cycle; Output duty cycle 40% to 60%, $V_{OL} < 0.5V$, $V_{OH} > 2.4V$. All channels switching in phase.



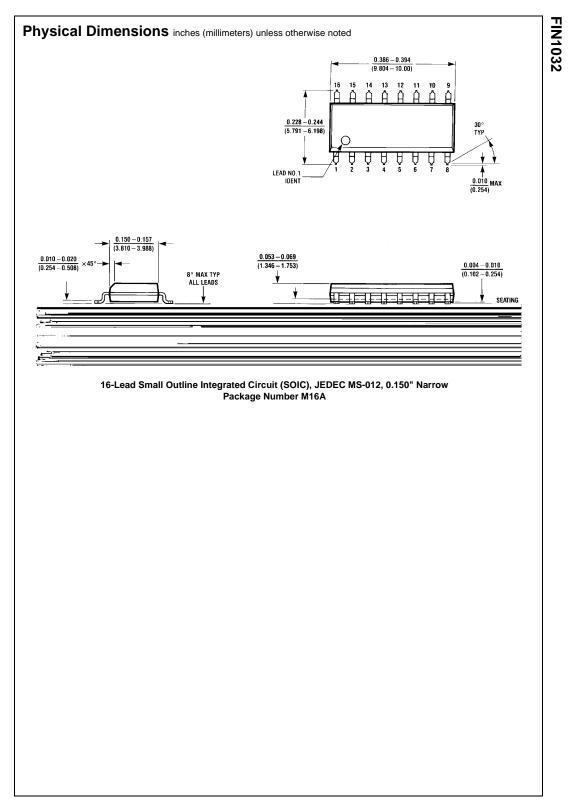
Note A: All input pulses have frequency = 10MHz, $t_R \mbox{ or } t_F = 1 \mbox{ns}$

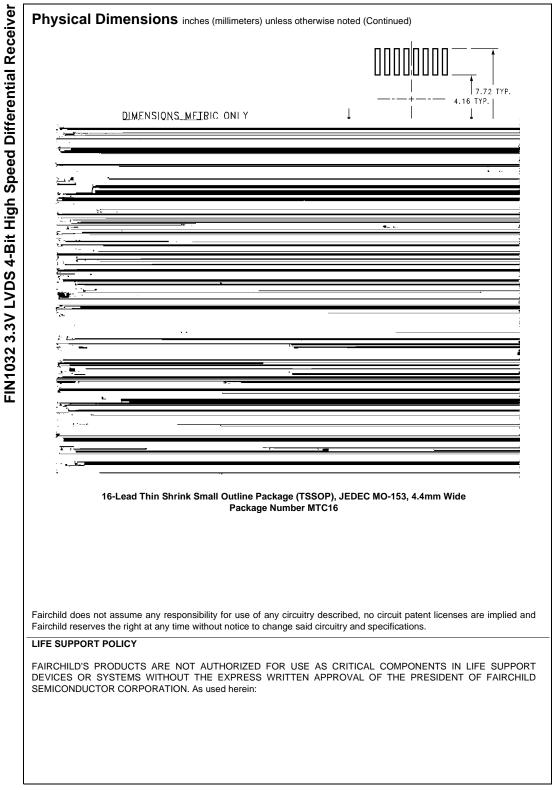
Note B: \mathbf{C}_L includes all probe and jig capacitances

FIGURE 1. Differential Receiver Voltage Definitions and Propagation Delay and Transition Time Test Circuit

TABLE 1. Receiver Minimum and Maximum Input Threshold Test Voltages

Applied V	oltages (V)	Resulting Differential Input Voltage (mA)	Resulting Common Mode Input Voltage (V)
VIA	V _{IB}	V _{ID}	V _{IC}
1.25	1.15	100	1.2
1.15	1.25	-100	1.2
2.4	2.3	100	2.35
2.3	2.4	-100	2.35
0.1	0	100	0.05
0	0.1	-100	0.05
1.5	0.9	600	1.2
0.9	1.5	-600	1.2
2.4	1.8	600	2.1
1.8	2.4	-600	2.1
0.6	0	600	0.3
0	0.6	-600	0.3





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